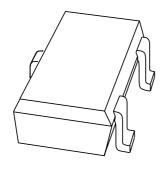
DISCRETE SEMICONDUCTORS

DATA SHEET



BAV199WLow-leakage double diode

Product data sheet Supersedes data of 1998 Jan 09 1999 May 11



Low-leakage double diode

BAV199W

FEATURES

- Small plastic SMD package
- Low leakage current: typ. 3 pA
- Switching time: typ. 0.8 μs
- Continuous reverse voltage: max. 75 V
- Repetitive peak reverse voltage: max. 85 V
- Repetitive peak forward current: max. 500 mA.

APPLICATIONS

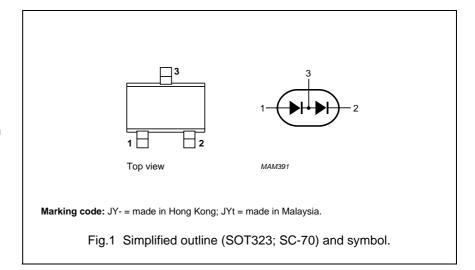
 Low-leakage current applications in surface mounted circuits.

DESCRIPTION

Epitaxial, medium-speed switching, double diode in a small plastic SOT323 (SC-70) SMD package. The diodes are connected in series.

PINNING

PIN	DESCRIPTION		
1	anode		
2	cathode		
3	cathode; anode		



LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT			
Per diode u	Per diode unless otherwise specified							
V_{RRM}	repetitive peak reverse voltage		_	85	V			
V_R	continuous reverse voltage		_	75	V			
I _F	continuous forward current	single diode loaded; T _s = 90 °C; see Fig.2	_	135	mA			
		double diode loaded; T _s = 90 °C; see Fig.2	_	110	mA			
I _{FRM}	repetitive peak forward current		_	500	mA			
I _{FSM}	non-repetitive peak forward current	square wave; T _j = 25 °C prior to surge; see Fig.4						
		$t_p = 1 \mu s$	_	4	Α			
		$t_p = 1 \text{ ms}$	_	1	Α			
		$t_p = 1 \text{ s}$	_	0.5	Α			
P _{tot}	total power dissipation	single diode loaded; T _s = 90 °C	_	150	mW			
		double diode loaded; T _s = 90 °C	_	240	mW			
T _{stg}	storage temperature		-65	+150	°C			
Tj	junction temperature		_	150	°C			

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Low-leakage double diode

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ELECTRICAL CHARACTERISTICS

 $T_j = 25$ °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT		
Per diode	Per diode						
V _F	forward voltage	see Fig.3					
		I _F = 1 mA	_	900	mV		
		I _F = 10 mA	_	1000	mV		
		I _F = 50 mA	_	1100	mV		
		I _F = 150 mA	_	1250	mV		
I _R	reverse current	see Fig.5					
		V _R = 75 V	0.003	5	nA		
		V _R = 75 V; T _j = 150 °C	3	80	nA		
C _d	diode capacitance	$f = 1 \text{ MHz}; V_R = 0; \text{ see Fig.6}$		_	pF		
t _{rr}	reverse recovery time	when switched from $I_F = 10 \text{ mA to}$ 0.3		3	μs		
		I_R = 10 mA; R_L = 100 Ω ; measured at I_R = 1 mA; see Fig.7					

THERMAL CHARACTERISTICS

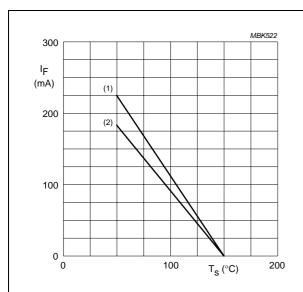
SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R _{th j-s}	thermal resistance from junction to soldering point	T _s = 90 °C	400	K/W

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Low-leakage double diode

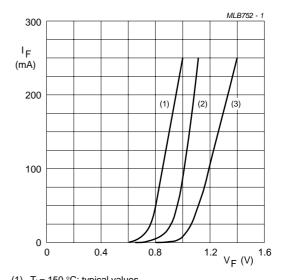
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GRAPHICAL DATA



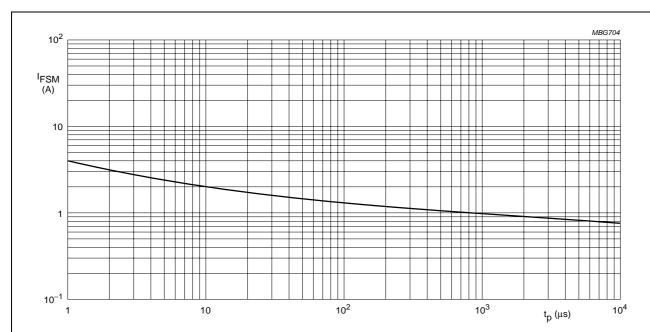
- (1) Single diode loaded.
- (2) Double diodes loaded.

Fig.2 Maximum permissible continuous forward current as a function of soldering point temperature; per diode.



- (1) $T_i = 150 \,^{\circ}\text{C}$; typical values.
- (2) $T_i = 25$ °C; typical values.
- (3) $T_j = 25$ °C; maximum values.

Forward current as a function of forward voltage; per diode.



Based on square wave currents. $T_i = 25$ °C prior to surge.

Fig.4 Maximum permissible non-repetitive peak forward current as a function of pulse duration per diode.

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Low-leakage double diode

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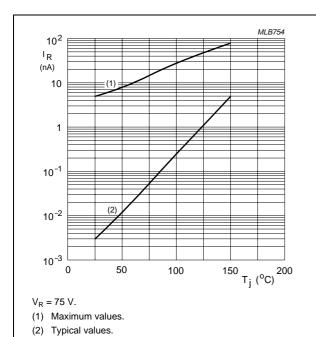


Fig.5 Reverse current as a function of junction temperature; per diode.

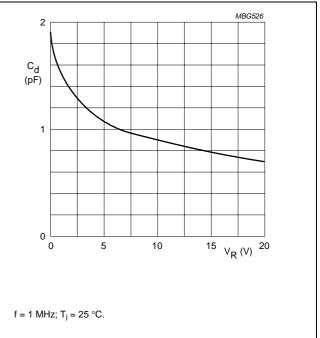
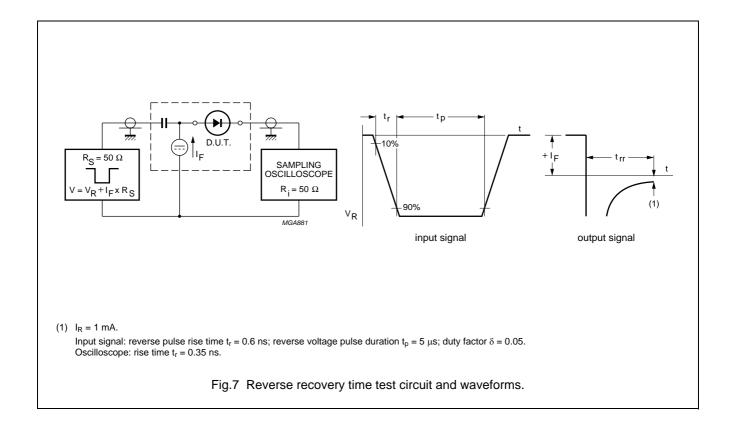


Fig.6 Diode capacitance as a function of reverse voltage; per diode; typical values.



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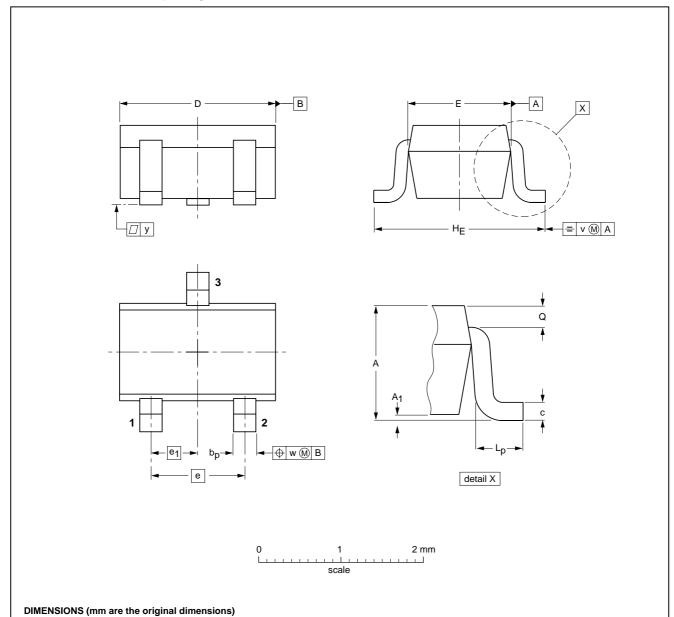
Low-leakage double diode

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PACKAGE OUTLINE

Plastic surface mounted package; 3 leads

SOT323



OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE

SC-70

e₁

0.65

 ${\sf H}_{\sf E}$

Lp

0.45

Q

0.2

97-02-28

Ε

1.3

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Α₁

max

 b_p

0.4

0.25

UNIT

SOT323

Low-leakage double diode

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DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

Notes

- 1. Please consult the most recently issued document before initiating or completing a design.
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